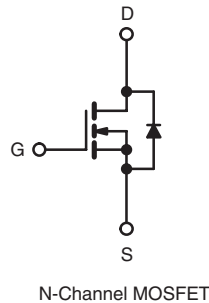
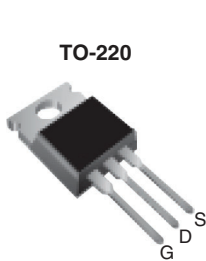


Power MOSFET

PRODUCT SUMMARY

V_{DS} (V)	100	
$R_{DS(on)}$ (Ω)	$V_{GS} = 5.0$ V	0.077
Q_g (Max.) (nC)	64	
Q_{gs} (nC)	9.4	
Q_{gd} (nC)	27	
Configuration	Single	



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(on)}$ Specified at $V_{GS} = 4$ V and 5 V
- 175 °C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Lead (Pb)-free Available



RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION

Package	TO-220
Lead (Pb)-free	IRL540PbF SiHL540-E3
SnPb	IRL540 SiHL540

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 10	
Continuous Drain Current	V_{GS} at 5.0 V	$T_C = 25$ °C	A
		$T_C = 100$ °C	
Pulsed Drain Current ^a	I_{DM}	110	
Linear Derating Factor		1.0	W/°C
Single Pulse Avalanche Energy ^b	E_{AS}	440	mJ
Avalanche Current ^a	I_{AR}	28	A
Repetitive Avalanche Energy ^a	E_{AR}	15	mJ
Maximum Power Dissipation	P_D	150	W
Peak Diode Recovery dV/dt ^c	dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

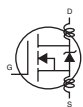
- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 25$ V, starting $T_J = 25$ °C, $L = 841$ μ H, $R_G = 25$ Ω , $I_{AS} = 28$ A (see fig. 12c).
- $I_{SD} \leq 28$ A, $dI/dt \leq 170$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 175$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

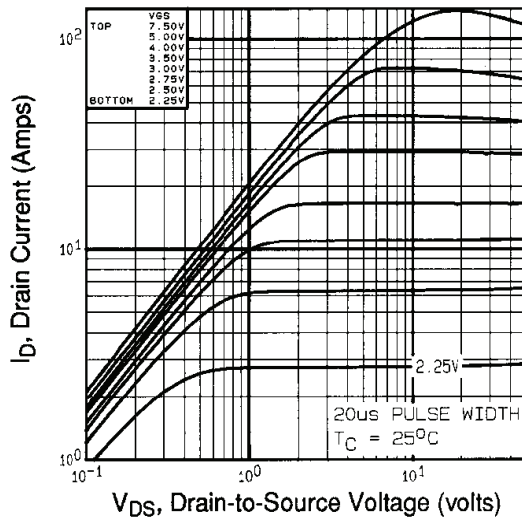
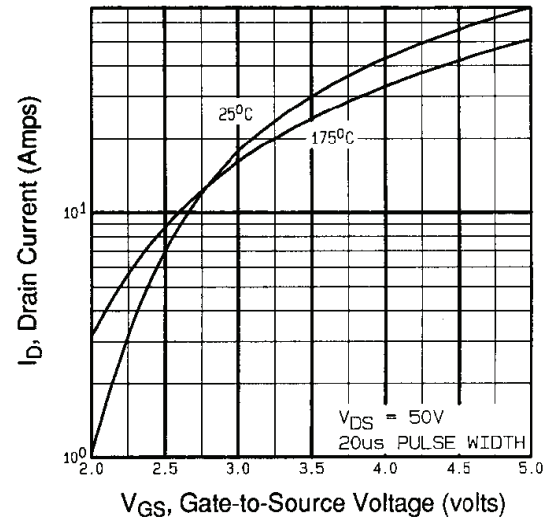
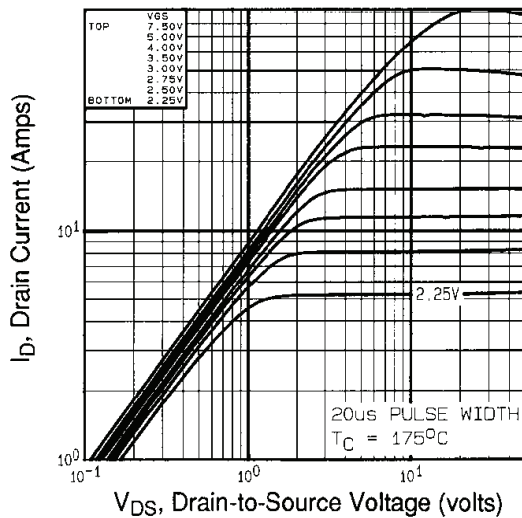
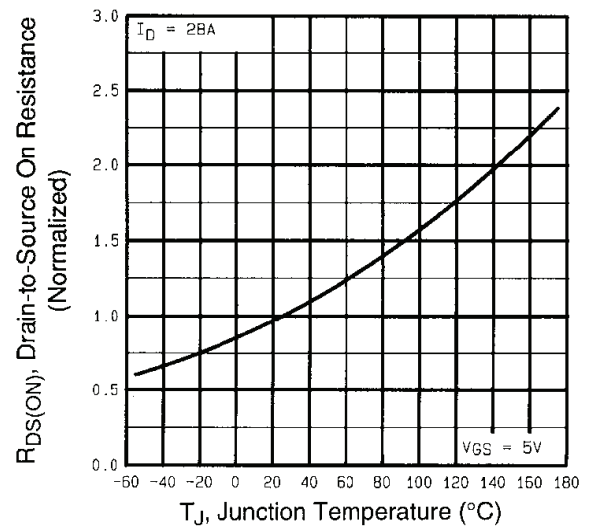
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

SPECIFICATIONS $T_J = 25\text{ °C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		100	-	-	V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, I _D = 1 mA		-	0.12	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		1.0	-	2.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 10 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V		-	-	25	μA
		V _{DS} = 80 V, V _{GS} = 0 V, T _J = 150 °C		-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 5.0 V	I _D = 17 A ^b	-	-	0.077	Ω
		V _{GS} = 4.0 V	I _D = 14 A ^b	-	-	0.11	
Forward Transconductance	g _{fs}	V _{DS} = 50 V, I _D = 17 A		12	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	2200	-	pF
Output Capacitance	C _{oss}			-	560	-	
Reverse Transfer Capacitance	C _{rss}			-	140	-	
Total Gate Charge	Q _g	V _{GS} = 5.0 V	I _D = 28 A, V _{DS} = 80 V, see fig. 6 and 13 ^b	-	-	64	nC
Gate-Source Charge	Q _{gs}			-	-	9.4	
Gate-Drain Charge	Q _{gd}			-	-	27	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 50 V, I _D = 28 A, R _G = 9.0 Ω, R _D = 1.7 Ω, see fig. 10 ^b		-	8.5	-	ns
Rise Time	t _r			-	170	-	
Turn-Off Delay Time	t _{d(off)}			-	35	-	
Fall Time	t _f			-	80	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact 		-	4.5	-	nH
Internal Source Inductance	L _S			-	7.5	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode 		-	-	28	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	110	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 28 A, V _{GS} = 0 V ^b		-	-	2.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 28 A, di/dt = 100 A/μs ^b		-	200	260	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.7	2.90	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 175^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

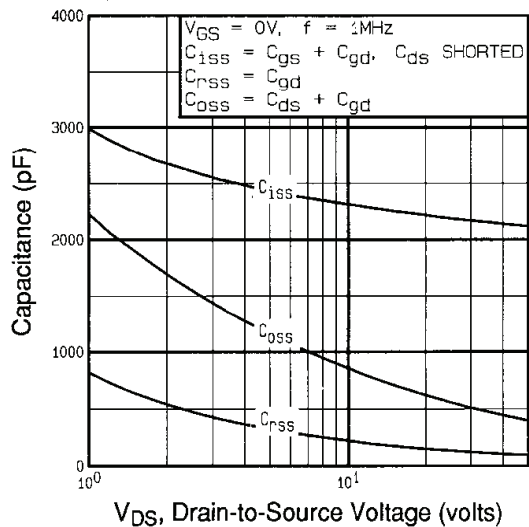


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

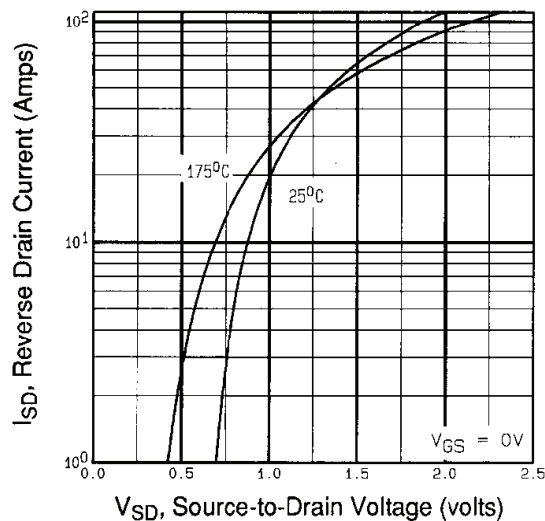


Fig. 7 - Typical Source-Drain Diode Forward Voltage

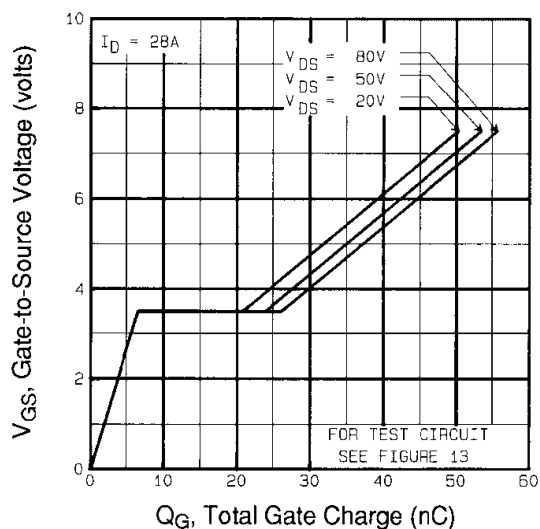


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

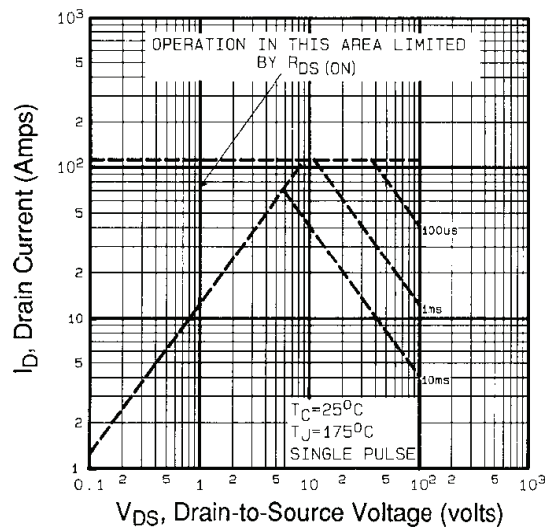


Fig. 8 - Maximum Safe Operating Area

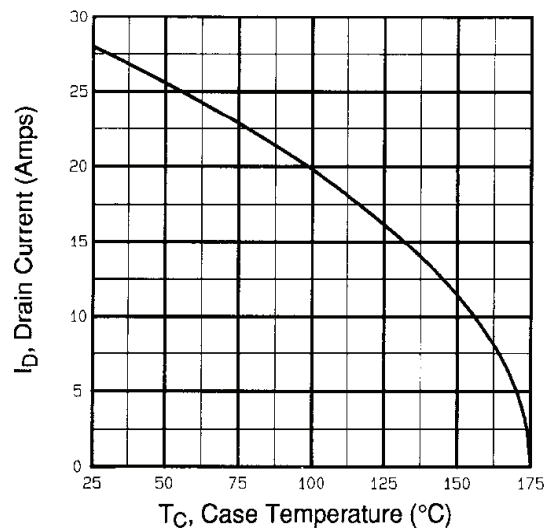


Fig. 9 - Maximum Safe Operating Area

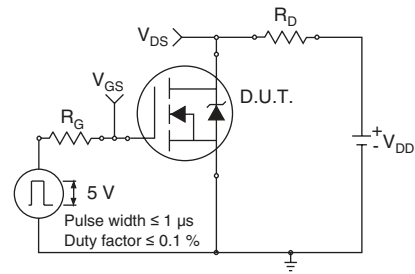


Fig. 10a - Switching Time Test Circuit

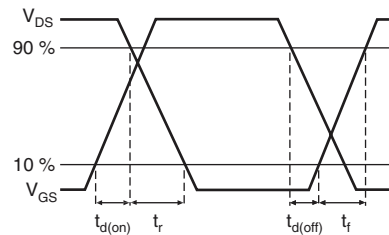


Fig. 10b - Switching Time Waveforms

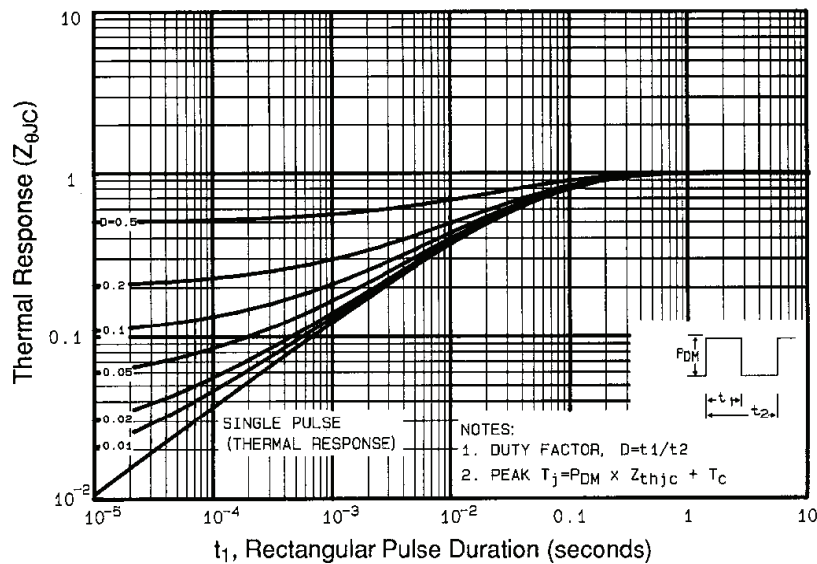


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

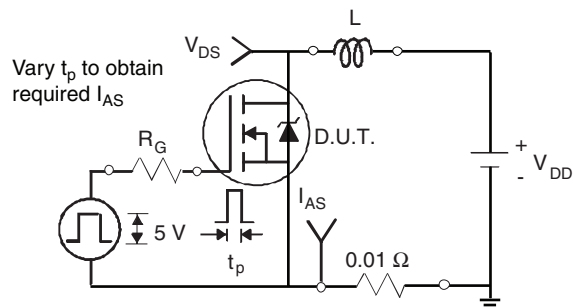


Fig. 12a - Unclamped Inductive Test Circuit

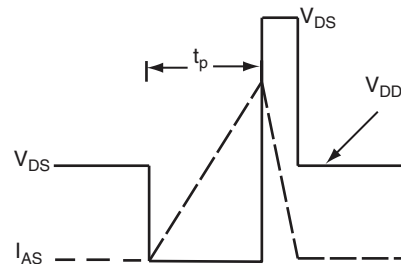


Fig. 12b - Unclamped Inductive Waveforms

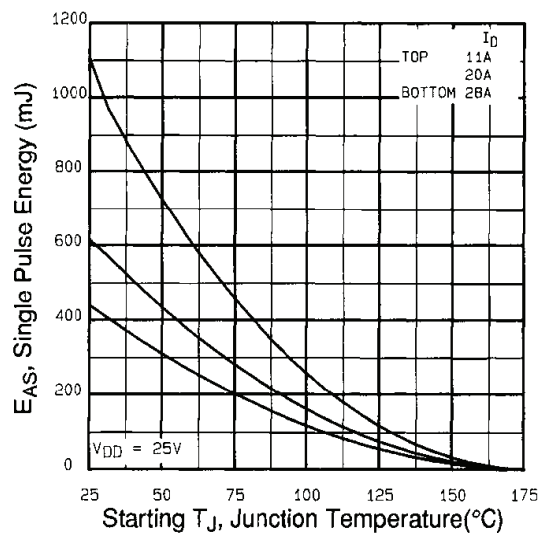


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

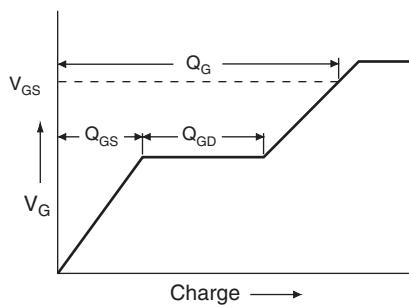


Fig. 13a - Basic Gate Charge Waveform

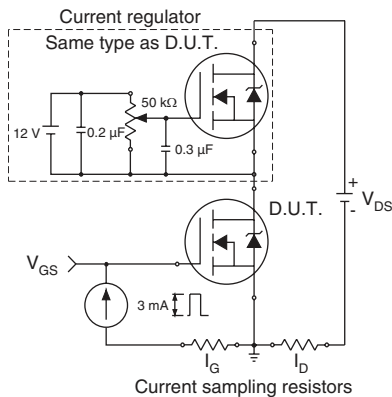


Fig. 13b - Gate Charge Test Circuit

① Driver gate drive

P.W. Period

$D = \frac{\text{P.W.}}{\text{Period}}$

$V_{GS} = 10 \text{ V}^*$

② D.U.T. I_{SD} waveform

Reverse recovery current

Body diode forward current

di/dt

③ D.U.T. V_{DS} waveform

Diode recovery dV/dt

V_{DD}

Body diode forward drop

Re-applied voltage

④ Inductor current

Ripple $\leq 5\%$

I_{SD}

* $V_{GS} = 5 \text{ V}$ for logic level devices

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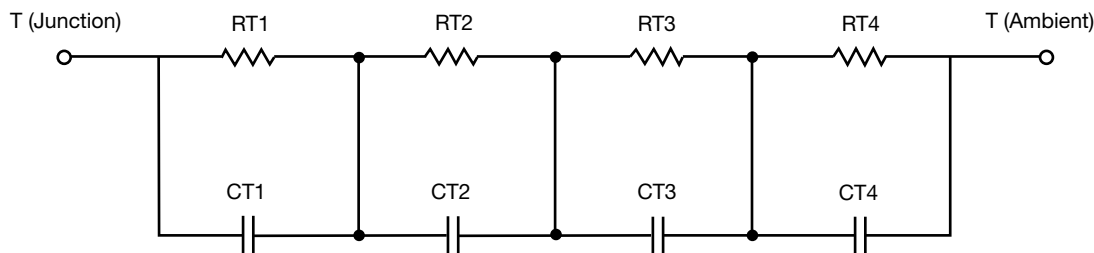
R-C Thermal Model Parameters

DESCRIPTION

The parametric values in the R-C thermal model have been derived using curve-fitting techniques. R-C values for the electrical circuit in the Foster/tank and Cauer/filter configurations are included. When implemented in P-SPICE, these values have matching characteristic curves to the single-pulse transient thermal impedance curves for the MOSFET.

These RC values can be used in the P-SPICE simulation to evaluate the thermal behavior of the MOSFET junction temperature under a defined power profile. These techniques are described in application note AN609, "Thermal Simulation of Power MOSFETs on the P-SPICE Platform".

R-C THERMAL MODEL FOR TANK CONFIGURATION

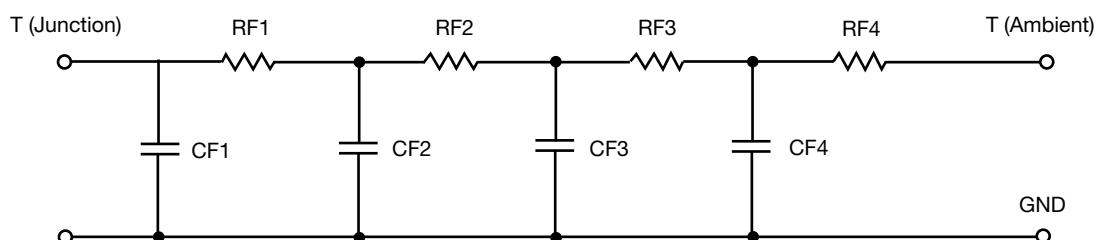


R-C VALUES FOR TANK CONFIGURATION			
THERMAL RESISTANCE (°C/W)			
Junction to	Ambient	Case	Foot
RT1	N/A	206.9037m	N/A
RT2	N/A	395.9929m	N/A
RT3	N/A	227.3703m	N/A
RT4	N/A	170.3629m	N/A
THERMAL CAPACITANCE (Joules/°C)			
Junction to	Ambient	Case	Foot
CT1	N/A	221.9978m	N/A
CT2	N/A	62.2678m	N/A
CT3	N/A	371.7813m	N/A
CT4	N/A	5.4775m	N/A

Note

N/A indicates not applicable

This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits.

R-C THERMAL MODEL FOR FILTER CONFIGURATION**R-C VALUES FOR FILTER CONFIGURATION**

THERMAL RESISTANCE (°C/W)			
Junction to	Ambient	Case	Foot
RF1	N/A	216.4514m	N/A
RF2	N/A	296.1503m	N/A
RF3	N/A	285.9659m	N/A
RF4	N/A	200.8331m	N/A
THERMAL CAPACITANCE (Joules/°C)			
Junction to	Ambient	Case	Foot
CF1	N/A	5.5720m	N/A
CF2	N/A	27.3086m	N/A
CF3	N/A	53.6821m	N/A
CF4	N/A	13.2668m	N/A

Note

N/A indicates not applicable

